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Nidec Advance Technology to Exhibit Products at SEMICON KOREA 2025

Nidec Advance Technology Corporation (“Nidec Advance Technology” or the “Company”) today announced that it will exhibit products at SEMICON KOREA 2025, an event to be held at COEX Convention Center in the city of Seoul from Wednesday, February 19 – Friday, February 21, 2025.



This upcoming exhibition will see Nidec Advance Technology showcase its state-of-the-art solutions, including: power semiconductor inspection equipment for IGBT/SiC, and test benches for driving motors of EVs, HEVs, and other vehicles; and a probe card, a wafer inspection tool developed and manufactured by Nidec SV Probe Corporation, a subsidiary of the Company. Also to be displayed at the event are Nidec Advance Technology’s semiconductor probe card, semiconductor package substrate electrical inspection system (GATS series), and power semiconductor electrical inspection system (NATS series), all of which embody the Company’s core technology of “measuring.”

Based on the inspection technologies it has nurtured so far, Nidec Advance Technology will propose its cutting-edge solutions, and new products and technologies that contribute to the future.

About SEMICON KOREA 2025:

- Period: Wednesday, February 19 – Friday, February 21, 2025
- Venue: COEX Convention Center in the city of Seoul
- Booth: C600, Hall C on the third floor
- Official website: <https://www.semiconkorea.org/en>

Nidec Advance Technology’s exhibits will include:

- High-voltage pressurized-structure probe card
- High-temperature/high-current probe card
- 2D-MEMS probe card
- Insulation/static/dynamic characteristics inspection equipment for IGBT/SiC modules (NATS-1000/1700 series)
- KGD testing equipment (NATS-1300 series)
- Dynamic reliability testing equipment for power semiconductor modules (NATS-8000 series)
- Reference inverter
- Test bench for EV drive motors (TDAS series)
- Semiconductor package substrate electrical inspection system (GATS-7000 series)
- Large substrate electrical inspection system for AI servers (GATS-8360)
- AC/DC multi-tester (R-700 series)
- Pin probe for ultra-high-precision inspections

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